Sonotron NDT

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**ISONIC 2010** 

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**Portable Ultrasonic Phased Array Flaw Detector and Recorder** 

#### **Phased Array**

32:32 phased array electronics - independently adjustable emitting and receiving aperture, parallel firing, A/D conversion, and on-the-fly real time digital phasing

POWER > LOW-BAT >

\* ISONIC 2010 1 0

- Phased array pulser receiver with image guided ray tracing True-to-Geometry / regular B-Scan and Sector Scan (S-Scan) with all-codes-compliant A-Scan evaluation
- Built-in automatic coupling monitor and lamination checker for wedged probes
- Multi-group / dual side scanning and imaging with use of one probe Encoded / time-based line scanning with Top (C-Scan), Side, End Mapping and 3D Viewing
- Automatic generating of editable defects list
- Independent gain per focal law adjustment: pure angle gain compensation for S-Scan, etc
- DAC, TCG Processing of diffracted and mode converted signals - defects sizing and pattern recognition
- 100% raw data capturing
- Powerful off-line data analysis toolkit -
- Intuitive User Interface
  - Sonotron NDT
- Light rugged case
- Sealed front panel keypad and mouse
- 6.5" bright touch screen



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# SIMPLICITY VERSATILITY RELIABILITY

#### **Conventional UT and TOFD**

- 1 channel Single / dual modes of
- pulsing/receiving
- True-to-Geometry flaw detection B-
- Scan straight / angle beam probes CB-Scan
- TOFD
  - DAC, DGS, TCG
- FFT signal analysis
- Ethernet and 2 X USB Ports Remote control UT over IP
- -
- -Built-in encoder port
- Regular A-Scan Thickness B-Scan

# General

**ISONIC 2010** uniquely combines phased array, conventional UT, and TOFD modalities providing 100% raw data recording and imaging. Along with superior portability, lightweight, and battery operation this makes it suitable for all kinds of every-day ultrasonic inspections

Phased array modality is performed by powerful 32:32 phased array electronics with independently adjustable emitting and receiving aperture, each may consist of 1 through 32 elements. Groups of phased array probe elements composing emitting and receiving aperture may be fully or partially matching or totally separated allowing flexible managing of incidence angles, focal distances, types of radiated and received waves including directly reflected and diffracted mode converted signals

Each channel is equipped with it's own A/D converter. Parallel firing, A/D conversion, and "on-the-fly" digital phasing are provided for every possible composition and size of the emitting and receiving aperture. Thus implementation of each focal law is completed within single pulsing/receiving cycle providing maximal possible inspection speed

**ISONIC 2010** is additionally equipped with independent channel for conventional UT and TOFD inspection and recording capable for both single and dual modes of pulsing/receiving

High ultrasonic performance is achieved through firing phased array, TOFD, and conventional probes with bipolar square wave initial pulse with wide-range-tunable duration and amplitude. Maximal amplitude of bipolar square wave initial pulse is 300 V pp for phased array and 400 V pp for conventional channel. High stability of the amplitude and shape of the initial pulse, boosting of all it's leading and falling edges, and electronic damping are provided by the special circuit significantly improving signal to noise ratio and resolution. Thus analogue gain for each modality is controllable over 0...100 dB range

640X480 pixels 6.5" bright touch screen provides optimal resolution / power consumption rate for the outdoor operation

## **Phased Array Modality**

**Phased array pulser receiver** is controlled through intuitive operating surface comprising user interface of conventional ultrasonic flaw detector and ray-tracing graphics. Type of wave generated in the material is controlled through key in of corresponding ultrasonic velocity. Trace of ultrasonic beam is truly imaged upon entering thickness, outside diameter, and other suitable geometry data characterizing object under test – this extremely simplifies creating of focal laws and calibration of the instrument as well

Signal evaluation fully compliant with conventional UT codes and procedures is applicable to A-Scans composed through implementing of various focal laws; DAC and TCG may be created either experimentally (up to 40 points) or theoretically through entering dB/mm (dB/inch) factor

**Cross-sectional insonification and imaging** of the material may be provided electronically with use of linear array probes through:

- Linear scanning with ultrasonic beam at predetermined incidence angle through reallocating of fixed size emitting/receiving aperture within entire array and composing of B-Scan image
- Sectorial scanning with ultrasonic beam produced by fixed emitting/receiving aperture through steering of incidence angle in the predetermined range and composing of S-Scan image
- Combining linear and sectorial scanning
- ♦ etc







B-Scan indication of **ISONIC 2010** representing inspection of composites for laminations: 1– scanning surface; 2 – bottom surface; 3 – lamination; 4 – A-Scan corresponding to the position of cursor over image



probe: 1 – angle gain compensation (AGC) is inactive; 2 – AGC is active; 3 – typical AGC graph

Regular (4) and true-to-geometry (5) S-Scan produced by ISONIC 2010 for compact reflector located at 20 mm depth of 40 mm thick plate. On the regular S-Scan single compact reflector is indicated twice for half (6) and full (7) skip detection while on the true-to-geometry S-Scan single reflector is shown in the real position for both ways of detection (8)

The effects of inequality of elements of linear array, varying sound path and loss in the delay line or wedge, dependency of energy of refracted wave and effective size of emitting/receiving aperture on incidence angle should be compensated to equalize the sensitivity over insonified cross-section. The unique feature of **ISONIC 2010** is the ability of managing *independently* adjustable focal laws within the same frame-composing sequence of pulsing/receiving shots so every focal law may me executed with individually adjusted gain, time base, and other core settings providing:

- Gain per Shot Correction for B-Scan
- Angle Gain Compensation for S-Scan
- True-to-Geometry imaging either B-Scan or S-Scan representing actual distribution of ultrasonic beams and true-to-location indication of defects in the cross-sectional view of the material



Weld inspection is the typical application benefited through use of *True-to-Geometry* imaging: upon defining geometry and entering dimensions operator is provided with intuitive ray tracing dialogue indicating actual coverage of the weld for the desired probe position and incidence angle steering range followed by live cross-sectional view either S-Scan or B-Scan *with true-to-location defects indication.* To ensure detection of variously oriented defects several S-Scan and B-Scan insonifications may be performed simultaneously with use of the same probe providing multi-group cross-sectional viewing and recording along whole inspected length. In addition to simple geometry butt joints *True-to-Geometry* imaging technology is applicable to longitudinal, nozzle, fillet, TKY, corner, elbow welds, and the like



Testing of solid and hollow shafts, axles, rods, billets, etc are among other applications improved significantly thanks to the easyto-interpret advantage of *True-to-Geometry* imaging vs regular S-Scan and B-Scan



True-to-Geometry S-Scan for single location (1) and complete cross sectional image of the hollow shaft with defects obtained after full circumference scanning (2) with linear array probe



True-to-Geometry S-Scan for longitudinal weld (3) and nozzle (4)

## 3D Data Presentation – Top (C-Scan), Side, and End Projection

**Views** is performed through line scanning with linear array probe either encoded or time-based at rectangle to the elements count direction. It is applicable for all types of cross-sectional insonification



For line scanning every cross sectional view is recorded along with complete sequence of raw data A-Scans it is composed of. C-Scan image is switcheable between distance (thickness or defects depth) and amplitude map



**Powerful off-line data analysis toolkit** includes playing back cross sectional views and A-Scans, gain manipulation in ±6dB range for all recorded A-Scans followed by corresponding image update, all-standards-compliant gate-based evaluation of echoes, geometry and amplitude filtering, image slicing and profiling, determining projection dimensions and area size of defects, 3D-viewing, etc



#### **Defects pattern analysis**

may be carried with use of well-known Delta Technique allowing distinguishing between low risk compact volumetric defects and cracks. Shear wave insonification of the evaluated discontinuity is performed with receiving of both direct shear wave and diffracted longitudinal wave echoes using the same linear array probe. Both echoes have been evaluated automatically providing digital readout of so called KLs value, based on which defect pattern is determined



Implementation of Delta Technique is extremely simplified as only one linear array probe placed into position of receiving maximized echo from evaluated discontinuity is used instead of pair of conventional shear wave and longitudinal wave probes. Corresponding screen of **ISONIC 2010** indicates 2 individually adjustable A-Scans comprising direct shear wave echo (1) with A<sub>S</sub> amplitude, diffracted longitudinal wave echo (2) with A<sub>L</sub> amplitude, and digital readout of K<sub>LS</sub> value (3) rating A<sub>S</sub>/A<sub>L</sub>

# **Conventional UT and TOFD modalities**

For single conventional channel operation **ISONIC 2010** provides fully featured A-Scan inspection as well as line scanning recording and imaging of the following types: thickness B-Scan; flaw detection B-Scan for angle beam and straight beam probes; CB-Scan for guided, surface, and shear wave probes inspections; TOFD. This fully covers scope of functions implemented by very well known **ISONIC 2005** / **ISONIC STAR** / **ISONIC 2020** portable ultrasonic flaw detector and recorder of Sonotron NDT – www.sonotronndt.com/i2005.htm

Comprehensive off-line analysis and data reporting toolkit for all kinds of data captured using conventional UT and TOFD modalities is built-in

## **Remote Control – UT over IP**

Remote control of **ISONIC 2010** is implemented through Ethernet port. The instrument is fully compatible with new **UT over IP** technology from Sonotron NDT allowing full control of the instrument, imaging, recording, and storage inspection data in the remote control computer

## Compliancy with international and national codes

ISONIC 2010 is fully compliant with the following codes

- ASME Code Case 2541 Use of Manual Phased Array Ultrasonic Examination Section V
- ASME Code Case 2557 Use of Manual Phased Array S-Scan Ultrasonic Examination Section V per Article 4
  Section V
- ASME Code Case 2558 Use of Manual Phased Array E-Scan Ultrasonic Examination Section V per Article 4
  Section V
- ASTM 1961–06 Standard Practice for Mechanized Ultrasonic Testing of Girth Welds Using Zonal Discrimination with Focused Search Units
- ASME Section I Rules for Construction of Power Boilers
- ASME Section VIII, Division 1 Rules for Construction of Pressure Vessels
- ASME Section VIII, Division 2 Rules for Construction of Pressure Vessels. Alternative Rules
- ASME Section VIII Article KE-3 Examination of Welds and Acceptance Criteria
- ASME Code Case 2235 Rev 9 Use of Ultrasonic Examination in Lieu of Radiography
- Non-Destructive Examination of Welded Joints Ultrasonic Examination of Welded Joints. British and European Standard BS EN 1714:1998
- Non-Destructive Examination of Welds Ultrasonic Examination Characterization of Indications in Welds. British and European Standard BS EN 1713:1998
- Calibration and Setting-Up of the Ultrasonic Time of Flight Diffraction (TOFD) Technique for the Detection, Location and Sizing of Flaws. British Standard BS 7706:1993
- WI 00121377, Welding Use Of Time-Of-Flight Diffraction Technique (TOFD) For Testing Of Welds. European Committee for Standardization Document # CEN/TC 121/SC 5/WG 2 N 146, issued Feb, 12, 2003
  - ASTM E 2373 04 Standard Practice for Use of the Ultrasonic Time of Flight Diffraction (TOFD) Technique
- Non-Destructive Testing Ultrasonic Examination Part 5: Characterization and Sizing of Discontinuities. British and European Standard BS EN 583-5:2001
- Non-Destructive Testing Ultrasonic Examination Part 2: Sensitivity and Range Setting. British and European Standard BS EN 583-2:2001
- Manufacture and Testing of Pressure Vessels. Non-Destructive Testing of Welded Joints. Minimum Requirement for Non-Destructive Testing Methods Appendix 1 to AD-Merkblatt HP5/3 (Germany).– Edition July 1989

# ISONIC 2010 – Technical Data

**Phased Arrav** Pulse Type: Initial Transition: Pulse Amplitude: Half Wave Pulse Duration: Probe Types: Emitting aperture: Phasing (emitting aperture): Receiving Aperture: Gain: Advanced Low Noise Design: Frequency Band: A/D Conversion Superimposing of receiving aperture signals: Phasing (receiving aperture): A-Scan Display Modes: DAC / TCG per focal law - for rectified and RF display:

Gates per focal law: Gate Start and Width:

Gate Threshold: Number of focal laws: Scanning and Imaging:

Method of data storage:

# **Conventional UT and TOFD**

Number of Channels: Pulse Type: Initial Transition: Pulse Amplitude: Half Wave Pulse Duration: Modes: Gain: Advanced Low Noise Design: Frequency Band: A/D Conversion: Digital Filter: A-Scan Display Modes: DAC / TCG – for rectified and RF display:

DGS: Gates: Gate Start and Width:

Gate Threshold: Measuring Functions – Digital Display Readout:

Freeze (A-Scans and Spectrum Graphs):

Scanning and Imaging: Standard Length of one Line Scanning record: Method of data storage:

#### General

PRF: On-Board Computer CPU: RAM: Internal Flash Memory - Quasi HDD: Screen: Controls: Interface: Operating System: Encoder interface: Standard Length of one Line Scanning record: Housing: Dimensions:

Weight:

**Bipolar Square Wave with electronically controlled damping** ≤7.5 ns (10-90% for rising edges / 90-10% for falling edges) Smoothly tunable (12 levels) 50V ... 300 V pp into 50  $\Omega$ 50...600 ns controllable in 10 ns step Linear / Ring Array 1...32 0...100 µs with 5 ns resolution 1...32 0...100 dB controllable in 0.5 dB resolution 85  $\mu V$  peak to peak input referred to 80 dB gain / 25 MHz bandwidth 0.2 ... 25 MHz Wide Band 100 MHz 16 bit On-the-fly, no multiplexing involved On-the-fly 0...100 µs with 5 ns resolution RF, Rectified (Full Wave / Negative or Positive Half Wave) Theoretical – dB/mm (dB/") Experimental – through recording echoes from several reflectors 46 dB Dynamic Range, Slope  $\leq$  20 dB/µs, Capacity  $\leq$  40 points 2 Independent Gates / unlimitedly expandable Controllable over whole variety of A-Scan Display Delay and A-Scan Range in 0.1 mm /// 0.001" resolution 5...95 % of A-Scan height controllable in 1 % resolution 8192 B-Scan (E-Scan) – regular and True-To-Geometry Sector Scan (S-Scan) – regular and True-To-Geometry One-probe multi-group image composed from several B- and S-Scans Top (C-Scan), Side, End View imaging formed through encoded / time-based line scanning, 3D-Viewer 100% raw data capturing

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- **Bipolar Square Wave with electronically controlled damping** ≤7.5 ns (10-90% for rising edges / 90-10% for falling edges) Smoothly tunable (12 levels) 50V ... 400 V pp into 50 Ω 50...600 ns independently controllable in 10 ns step Single / Dual 0...100 dB controllable in 0.5 dB resolution 85 µV peak to peak input referred to 80 dB gain / 25 MHz bandwidth 0.2 ... 25 MHz Wide Band 100 MHz 16 bit 32-Taps FIR band pass with controllable lower and upper frequency limits RF, Rectified (Full Wave / Negative or Positive Half Wave), Signal's Spectrum (FFT Graph) Theoretical – dB/mm (dB/") Experimental – through recording echoes from several reflectors 46 dB Dynamic Range, Slope  $\leq$  20 dB/µs, Capacity  $\leq$  40 points Standard Library for 18 probes / unlimitedly expandable 2 Independent Gates / unlimitedly expandable Controllable over whole variety of A-Scan Display Delay and A-Scan Range in 0.1 mm /// 0.001" resolution 5...95 % of A-Scan height controllable in 1 % resolution 27 automatic functions / expandable; Dual Ultrasound Velocity Measurement Mode for Multi-Layer Structures; Curved Surface / Thickness / Skip correction for angle beam probes; Ultrasound velocity and Probe Delay Auto-Calibration for all types of probes Freeze All – A-Scans and Spectrum Graphs / Freeze Peak – A-Scans / All measurements functions, manipulating Gates, and +6dB Gain varying are available for frozen signals Thickness Profile B-Scan, Cross-sectional B-Scan, Plane View CB-Scan, TOFD 50...20000 mm (2"...800"), automatic scrolling 100% raw data capturing 10...5000 Hz controllable in 1 Hz resolution AMD LX 800 - 500MHz 1 Gigabyte 4 Gigabytes Sun readable 6.5" touch screen 640 × 480
- 10...5000 Hz controllable in 1 Hz resolution AMD LX 800 - 500MHz 1 Gigabyte 4 Gigabytes Sun readable 6.5" touch screen 640 × 480 Sealed keyboard and mouse 2 × USB, Ethernet Windows™XP Embedded Incremental TTL encoder 50...2000 mm (2"...800"), automatic scrolling IP 53 rugged aluminum case with carrying handle 265x156x101 mm (10.43" v6 14" v3.98") - without bat

265×156×101 mm (10.43"×6.14"×3.98") - without battery 265×156×139 mm (10.43"×6.14"×5.47") - with battery 2.500 kg (5.50 lbs) - without battery 3.430 kg (7.55 lbs) - with battery